



POWER-MOS FET

FIELD EFFECT POWER TRANSISTOR

**IRF510,511
D84BL2,K2**

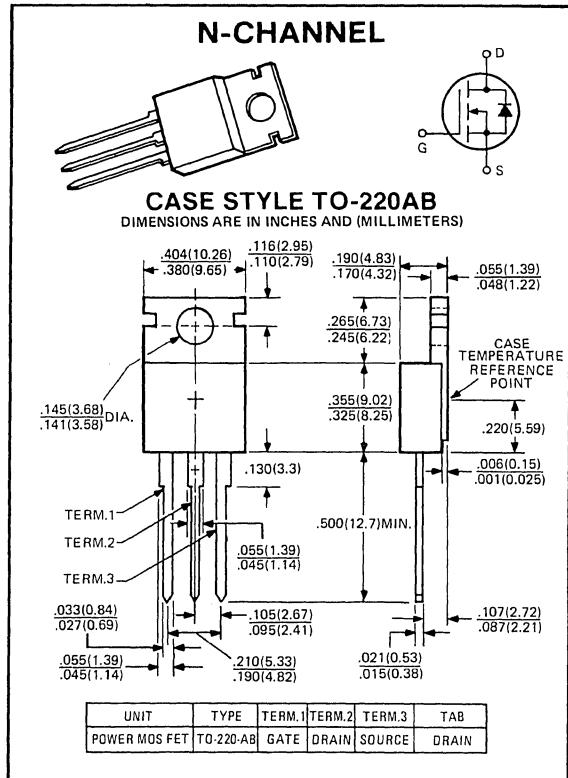
4.0 AMPERES
100, 60 VOLTS
 $R_{DS(ON)} = 0.6 \Omega$

The IRF510, 511 Series is an N-Channel Enhancement-mode Power MOSFET utilizing GE's advanced Power DMOS technology to achieve low on-resistance with excellent device ruggedness and reliability.

The IRF510, 511 design has been optimized to give superior performance in most switching applications including: switching power supplies, inverters, converters and solenoid/relay drivers. Also, the extended safe operating area with good linear transfer characteristics makes it well suited for many linear applications such as audio amplifiers and servo motors.

Features

- Polysilicon gate — Improved stability and reliability
- No secondary breakdown — Excellent ruggedness
- Ultra-fast switching — Independent of temperature
- Voltage controlled — High transconductance
- Low input capacitance — Reduced drive requirement
- Excellent thermal stability — Ease of paralleling



maximum ratings ($T_C = 25^\circ\text{C}$) (unless otherwise specified)

RATING	SYMBOL	IRF510/D84BL2	IRF511/D84BK2	UNITS
Drain-Source Voltage	V_{DSS}	100	60	Volts
Drain-Gate Voltage, $R_{GS} = 1\text{M}\Omega$	V_{DGR}	100	60	Volts
Continuous Drain Current @ $T_C = 25^\circ\text{C}$ @ $T_C = 100^\circ\text{C}$	I_D	4.0 2.5	4.0 2.5	A A
Pulsed Drain Current ⁽¹⁾	I_{DM}	16	16	A
Gate-Source Voltage	V_{GS}	± 20	± 20	Volts
Total Power Dissipation @ $T_C = 25^\circ\text{C}$ Derate Above 25°C	P_D	20 0.16	20 0.16	Watts $\text{W}/^\circ\text{C}$
Operating and Storage Junction Temperature Range	T_J, T_{STG}	-55 to 150	-55 to 150	$^\circ\text{C}$

thermal characteristics

Thermal Resistance, Junction to Case	$R_{\theta JC}$	6.4	6.4	$^\circ\text{C}/\text{W}$
Thermal Resistance, Junction to Ambient	$R_{\theta JA}$	80	80	$^\circ\text{C}/\text{W}$
Maximum Lead Temperature for Soldering Purposes: $\frac{1}{6}$ " from Case for 5 Seconds	T_L	260	260	$^\circ\text{C}$

(1) Repetitive Rating: Pulse width limited by max. junction temperature.

electrical characteristics ($T_C = 25^\circ\text{C}$) (unless otherwise specified)

CHARACTERISTIC	SYMBOL	MIN	TYP	MAX	UNIT
off characteristics					
Drain-Source Breakdown Voltage ($V_{GS} = 0\text{V}$, $I_D = 250\ \mu\text{A}$)	IRF510/D84BL2 IRF511/D84BK2	BVDSS 60	—	—	Volts
Zero Gate Voltage Drain Current ($V_{DS} = \text{Max Rating}$, $V_{GS} = 0\text{V}$, $T_C = 25^\circ\text{C}$) ($V_{DS} = \text{Max Rating} \times 0.8$, $V_{GS} = 0\text{V}$, $T_C = 125^\circ\text{C}$)	I_{DSS}	— —	— —	250 1000	μA
Gate-Source Leakage Current ($V_{GS} = \pm 20\text{V}$)	I_{GSS}	—	—	± 500	nA

on characteristics*

Gate Threshold Voltage ($V_{DS} = V_{GS}$, $I_D = 250\ \text{mA}$)	$T_C = 25^\circ\text{C}$	$V_{GS(\text{TH})}$	2.0	—	4.0	Volts
On-State Drain Current ($V_{GS} = 10\text{V}$, $V_{DS} = 10\text{V}$)		$V_{DS(\text{ON})}$	4.0	—	—	Volts
Static Drain-Source On-State Resistance ($V_{GS} = 10\text{V}$, $I_D = 2\text{A}$)		$R_{DS(\text{ON})}$	—	—	0.6	Ohms
Forward Transconductance ($I_D = 2\text{A}$)		g_{fs}	.8	1.1	—	mhos

dynamic characteristics

Input Capacitance	$V_{GS} = 0\text{V}$	C_{iss}	—	145	200	pF
Output Capacitance	$V_{DS} = 25\text{V}$	C_{oss}	—	65	100	pF
Reverse Transfer Capacitance	f = 1 MHz	C_{rss}	—	20	25	pF

switching characteristics*

Turn-on Delay Time	$V_{DS} = 30\text{V}$	$t_{d(\text{on})}$	—	15	—	ns
Rise Time	$I_D = 1.5\text{A}$, $V_{GS} = 15\text{V}$	t_r	—	15	—	ns
Turn-off Delay Time	$R_{GEN} = 50\Omega$, $R_{GS} = 12.5\Omega$	$t_{d(\text{off})}$	—	30	—	ns
Fall Time	(R_{GS} (EQUIV.) = 10Ω)	t_f	—	10	—	ns

source-drain diode ratings and characteristics*

Continuous Source Current	I_S	—	—	4.0	A
Pulsed Source Current	I_{SM}	—	—	16	A
Diode Forward Voltage ($T_C = 25^\circ\text{C}$, $V_{GS} = 0\text{V}$, $I_S = 4\text{A}$)	V_{SD}	—	1.3	2.5	Volts
Reverse Recovery Time ($I_S = 4\text{A}$, $dI_S/dt = 100\text{A}/\mu\text{s}$, $V_{DS} = 40\text{V}$ max., $T_C = 125^\circ\text{C}$)	t_{rr} Q_{RR}	— —	100 .3	— —	ns μC

*Pulse Test: Pulse width $\leq 300\ \mu\text{s}$, duty cycle $\leq 2\%$

